

# Direct Correlative Nanoscopy Imaging of 2D materials

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2D transition metal dichalcogenides (TMDCs) materials are considered of very high potential semiconductors for future nanosized electronic and optoelectronic devices. An information-rich nanoscale characterization technique is required to qualify these materials and assist in the deployment of 2D material-based applications.

Scanning Probe Microscopy (SPM) is a powerful technique to image physical properties of 2D materials, such as topography, surface potential or other electrical properties. Combining SPM and Raman in a single instrumentation is extremely powerful as it makes imaging of both chemical and physical properties possible. As Raman is diffraction limited, only plasmon enhanced Raman and photoluminescence spectroscopies yield correlated electrical and chemical information down to the nanoscale.

In this talk, we will report on Tip-Enhanced Photoluminescence (TEPL) and Tip-Enhanced Raman spectroscopy (TERS) data obtained on single crystal TMDC flakes directly grown on SiO<sub>2</sub>/Si. TEPL and TERS images will be correlated with contact potential difference and capacitance maps as results of Kelvin force probe microscopy acquisition.

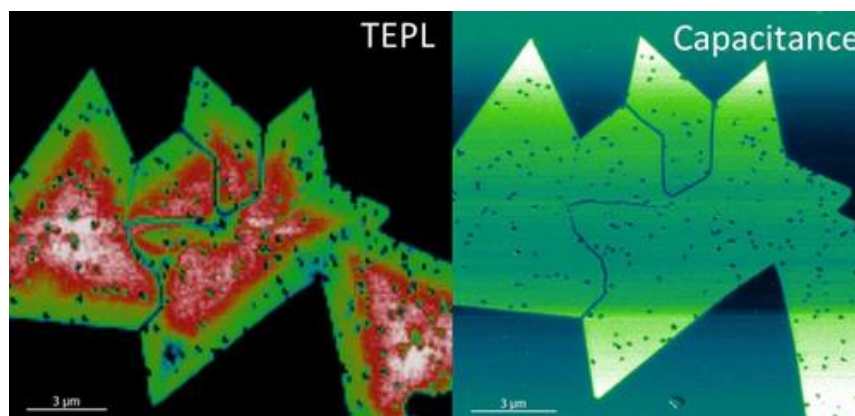
Beside these semiconductor/dielectric (SiO<sub>2</sub>) interfaces, probing TMDC/metal interfaces is also essential to integrate TMDCs in 2D or 3D complex structures of devices. We will show results from WS<sub>2</sub> on silver and WSe<sub>2</sub> and MoS<sub>2</sub> on gold. Such transferred surfaces exhibit nanoscale inhomogeneities observed in correlated CPD and Raman maps.

Finally, TEPL together with AFM topography data on a lateral single layer WS<sub>2</sub>/WS<sub>x</sub>Se<sub>1-x</sub>/WSe<sub>2</sub> heterostructure grown on SiO<sub>2</sub>/Si will be presented: nanoscale PL response variations are observed beyond the smooth nano-resolution topography.

## References

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- [4] *Chem. Commun.* 57, 6895 (2021)
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## Figures



**Figure 1:** Correlated Tip-enhanced Photoluminescence and Capacitance measurements on WSe<sub>2</sub> flakes.